Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/792,293	LOEW ET AL.
Examiner	Art Unit
Patrick J. Lee	2878

SEARCHED					
Class	Subclass	Date	Examiner		
250	205, 208.1,	15/15/02	PL		
	214C	12/4/05	PL		
327	514	12/14/2005	PL		
313	531	12/14/2005	PL		
315	10	12/14/2005	PL		
315	156-159	12/14/2005	PL		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/12/2005	PL		
Consulted w/ S. Allen AU 2878 CL 250	12/13/2005	PL		
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/14/2005	PL		